

FORUM-MD Workshop

“AI in a metrological context: AI for metrology and metrology for AI”

11 March 2026, BIPM, Sèvres (9h00-17h30 UTC+1)

09h00-09h15	Welcome and Introduction	Cornelia Denz (PTB, Germany)
09h15-10h45	Session1: Metrology for AI systems: Assessment and methodologies	Chair: Peter Blattner (METAS, Switzerland)
09h15-09h45	1.1 <i>Conformity assessment schemes for AI systems</i>	Martina Paul (ISO/IEC JTC1 SC 42 JWG 6)
09h45-10h15	1.2 <i>Test and certification of safety-relevant AI applications</i>	Thomas Doms (AIQI, TÜV Austria)
10h15-10h45	1.3 <i>Metrics and data for testing of AI systems</i>	Rania Wazir (NoLeFa, leiwand.ai)
10h45-11h15	Coffee Break	
11h15-13h00	Session 2: AI for metrology: Improved metrological services and certificates	Chair: Louise Wright (NPL, UK)
11h15-11h45	2.1 <i>Smart Documents Vision</i>	Rodolfo Souza (INMETRO, Brasil)
11h45-12h15	2.2 <i>The Study on the Development Of a Calibration Certificate Application with AI</i>	Dong-Hun Ryu (Korea Testing Laboratory, Korea (Rep. of))
12h15-12h45	2.3 <i>Application of AI in Metrology</i>	Jeff Gust (Fluke, USA)
12h45-14h00	Lunch	
14h00-15h30	Session 3: Parallel Sessions	
AI Safety, Metrics & the role of NMIs <i>This session will discuss what is needed for AI safety and trustworthiness, examining the role of metrics, measurement & NMI's more broadly. Each speaker will present for ~20 minutes followed by a panel session involving all participants.</i>		Chair: Paul Duncan (NPL, UK) Speakers: Paul Duncan (NPL, UK) Martin Koval (CMI, Czechia) Martin Staněk (CMI, Czechia) David Filip (ISO/IEC JTC 1/SC 42 Artificial intelligence WG 3)

<i>AI best practice applications</i>	Chair: Louise Wright (NPL, UK)
This session will discuss some case studies of the use of AI within metrology, developed as case studies by the members of TG-AI	Speakers: Cui Shan (A*STAR, Singapore) Chris Barnes (NPL, UK) Wan-Ho CHO (KRISS, South Korea) Kseniia Sapozhnikova (VNIIM, Russia) Edgardo José Marchi (INTI, Argentina) Sebastian Heidenreich (PTB, Germany)

<i>Data quality, semantics & AI</i>	Chairs: Ryan White (NRC, Canada), Daniel Hutzschenreuter (PTB, Germany)
<p>“Data ready for AI: How do data quality and semantics interact with AI applications?”</p> <p>In response to the growth of AI, machine-actionable formats for data and metadata are steadily advanced to facilitate their usage with progressive data analysis tools. At the same time, AI tooling has a high potential in supporting experts in the digitalization of all kinds of sources of data by harvesting metadata and semantics.</p> <p>The parallel session will give valuable insights into developments of data and applications with AI. Experts from different areas of science and metrology will share their thoughts on benefits, challenges and needs in the context of Data quality, Semantics, and AI.</p>	<p>Speakers: James Cheney (University of Edinburgh, UK), Vyacheslav Tykhonov (CODATA)</p> <p>Round table discussion:</p> <p>James Cheney (University of Edinburgh, UK) Vyacheslav Tykhonov (CODATA) Steven Ellison (JCGM Working Group 1) Cristhian Paredes (BIPM) Jean-Laurent Hippolyte (NPL, UK)</p> <p><i>The round table discussion is followed by an open discussion among all participants of this session.</i></p>

15h30-16h00 Coffee Break

16h00-16h30	Wrap-up of the parallel sessions in the plenary	Chairs of parallel sessions
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16h30-17h30	<i>Podium discussion: Future role of AI at NMIs - assist or assess?</i>	Moderator: Hector Laiz (INTI, Argentina)
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Panelists: Louise Wright (NPL, UK), Cui Shan (A*STAR, Singapore), Frank Härtig (PTB, Germany), Rodolfo Souza (INMETRO, Brasil).

17h30 Closing the meeting